

Multi-Epi Super Junction MOSFET



Lead Free Package and Finish

Applications:

- Switch Mode Power Supply(SMPS)
- Uninterruptible Power Supply(UPS)
- PFC stages for server & telecom
- Consumer

Id	R _{DS(ON)} (Max.)	V _{DSS}
20A	190mΩ	650V

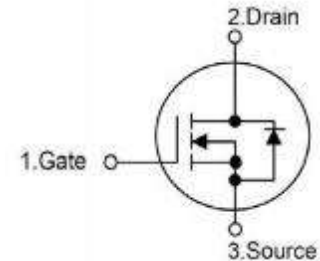
Features:

- New revolutionary high voltage technology
- Better R_{DS(on)} in TO-220F
- Ultra Low Gate Charge cause lower driving requirements
- Periodic avalanche rated
- Ultra low effective capacitances



TO-220F

Not to Scale



Ordering Information

Part Number	Package	Marking
RS65R190F	TO-220F	RS65R190F

Absolute Maximum Ratings T_c=25°C unless otherwise specified

Symbol	Parameter	RS65R190F	Units
V _{DSS}	Drain-to-Source Voltage	650	V
I _D	Continuous Drain Current (T _C = 25°C)	20	A
	Continuous Drain Current (T _C = 100°C)	12.7	
I _{DM}	Pulsed Drain Current (Note*1)	60	
P _D	Power Dissipation(T _c =25°C)	34	W
V _{GS}	Gate-to-Source Voltage	±30	V
EAS	Single Pulse Avalanche Energy	450	mJ
T _L TPKG	Maximum Temperature for Soldering	300 260	°C
	Leads at 0.063in(1.6mm)from Case for 10 seconds		
	Package Body for 10 seconds		
T _J and T _{STG}	Operating Junction and Storage Temperature Range	-55 to 150	

*Drain Current Limited by Maximum Junction Temperature

Caution:Stresses greater than those listed in the“Absolute Maximum Ratings”Table may cause permanent damage to the device.

Thermal Resistance

Symbol	Parameter	RS65R190F	Units	Test Conditions
R _{θJC}	Junction-to-Case	3.7	°C/W	Drain lead soldered to water cooled heatsink ,PD Adjusted for a peak junction temperature of +150°C .
R _{θJA}	Junction-to-Ambient	62		1 cubic foot chamber ,free air.

REASUNOS**RS65R190F****OFF Characteristics** $T_J=25^{\circ}\text{C}$ unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
BVDS	Drain-to-source Breakdown Voltage	650	--	--	V	$V_{GS} = 0V, I_D = 250\mu A, T_J = 25^{\circ}\text{C}$
		--	650	--	V	$V_{GS} = 0V, I_D = 250\mu A, T_J = 150^{\circ}\text{C}$
IDSS	Drain-to-Source Leakage Current	--	--	1.0	μA	$V_{DS}=700V, V_{GS}=0V$
IGSS	Gate-to-Source Forward Leakage	--	--	100	nA	$V_{GS}=+30V, V_{DS}=0V$
	Gate-to-Source Reverse Leakage	--	--	-100		$V_{GS}=-30V, V_{DS}=0V$

ON Characteristics $T_J=25^{\circ}\text{C}$ unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
RDS(on)	Static Drain-to-Source On-Resistance	--	170	190	m Ω	$V_{GS}=10V, I_D=7.3A$
VGS(TH)	Gate Threshold Voltage	2.0	--	4.0	V	$V_{GS}=V_{DS}, I_D=250\mu A$
R _G	Gate Resistance	--	3.0	--	Ω	$V_{GS} = 0V, f = 1.0\text{MHz}$

Resistive Switching Characteristics Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
td(ON)	Turn-on Delay Time	--	40	--	ns	$V_{DS}=350V$ $I_D=20A$ $R_G=25\Omega$ $V_{GS}=10V$
trise	Rise Time	--	75	--		
td(OFF)	Turn-OFF Delay Time	--	172	--		
tfall	Fall Time	--	54	--		

Dynamic Characteristics Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
Ciss	Input Capacitance	--	1820	--	pF	$V_{GS}=0V$ $V_{DS}=100V$ $f=1.0\text{MHz}$
Coss	Output Capacitance	--	82	--		
Crss	Reverse Transfer Capacitance	--	36	--		
Qg	Total Gate Charge	--	53	--	nC	$V_{DS}=560V$ $I_D=20A$ $V_{GS}=10V$
Qgs	Gate-to-Source Charge	--	13	--		
Qgd	Gate-to-Drain("Miller") Charge	--	20	--		

Source-Drain Diode Characteristics

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
IS	Continuous Source Current	--	--	20	A	Integral pn-diode in MOSFET
ISM	Maximum Pulsed Current	--	--	60	A	
VSD	Diode Forward Voltage	--	--	1.4	V	IS=20A, VGS=0V Tj=25°C
trr	Reverse Recovery Time	--	324	--	nS	VR=100V, VGS=0V IS=20A, di/dt=100A/μs
Qrr	Reverse Recovery Charge	--	9.4	--	μC	
Irrm	Peak Reverse Recovery Current	--	35.7	--	A	

Notes:

*1.Repetitive rating;pulse width limited by maximum junction temperature .

Typical Feature curve T_J=25°C, unless otherwise noted

Figure1. Output Characteristics

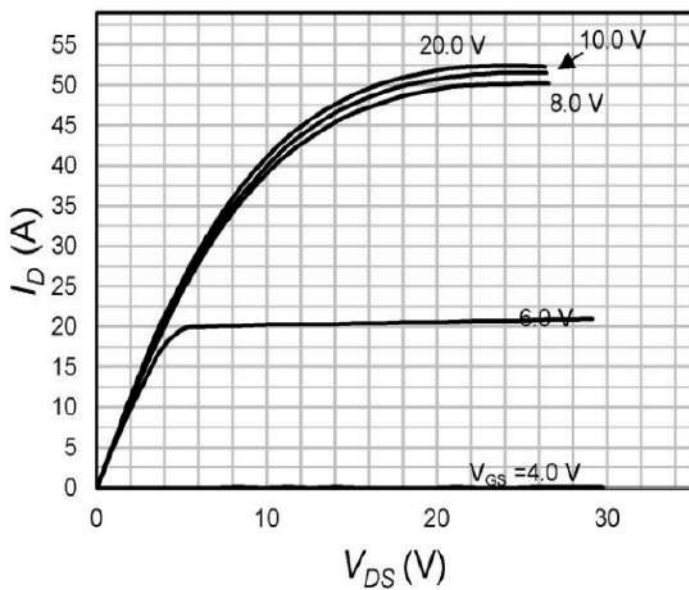


Figure2. Transfer Characteristics

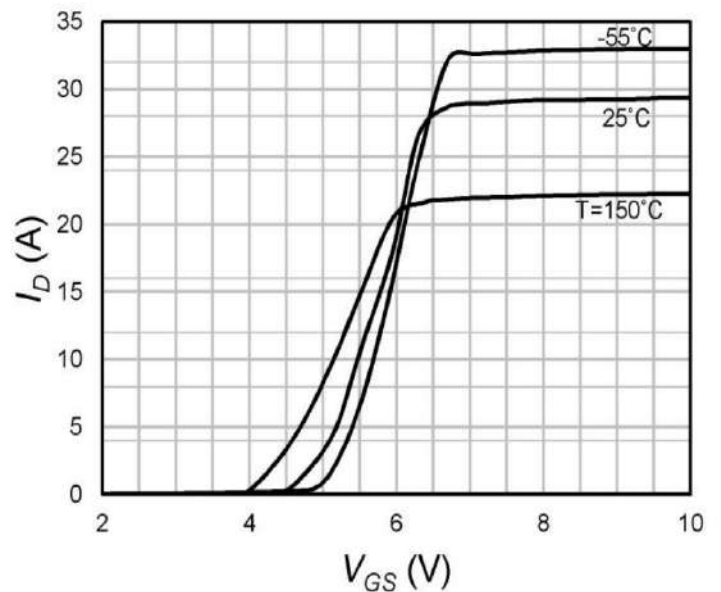


Figure 3. On-Resistance VS.Drain Current

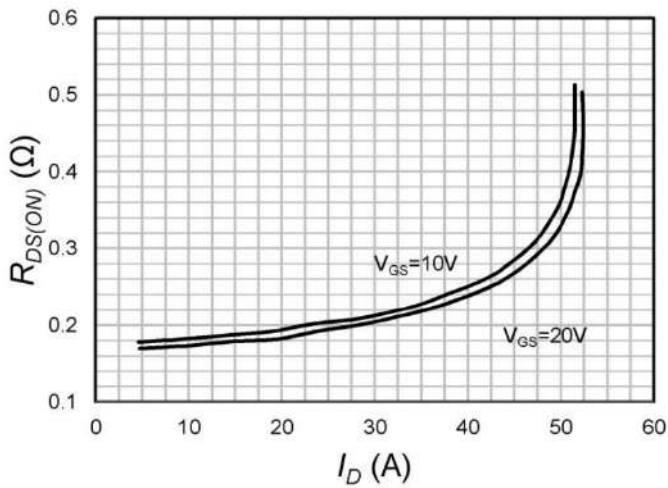


Figure 4. Capacitance

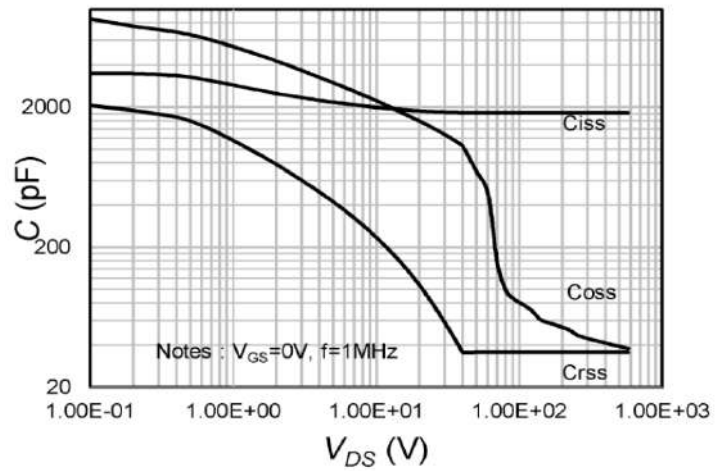


Figure 5. Gate Charge

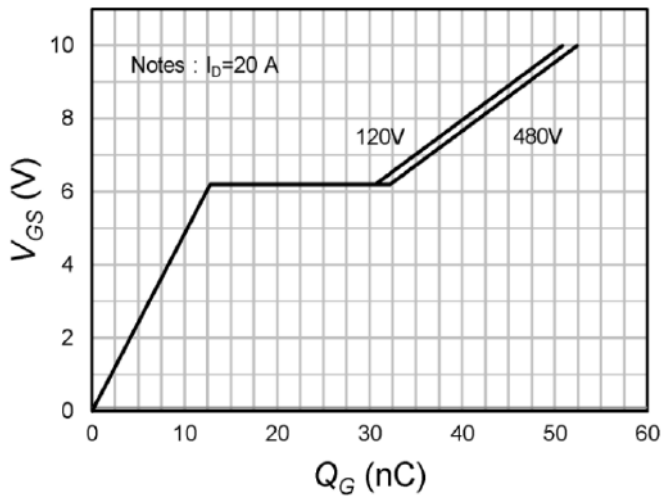


Figure 6. Body Diode Forward Voltage

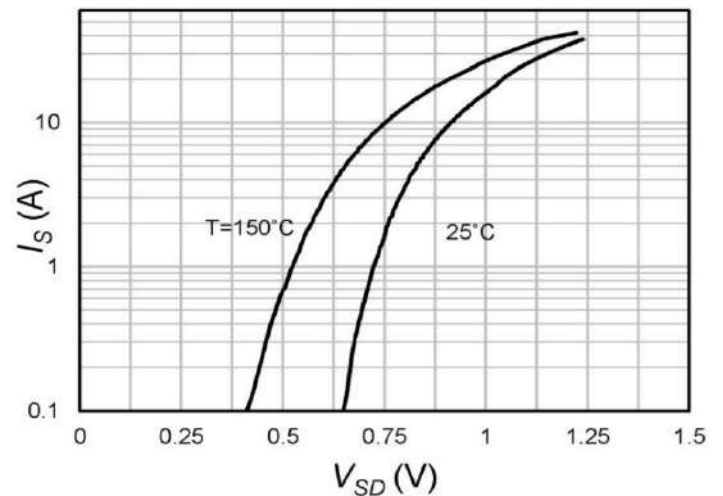


Figure 7. On-Resistance vs. Junction Temperature

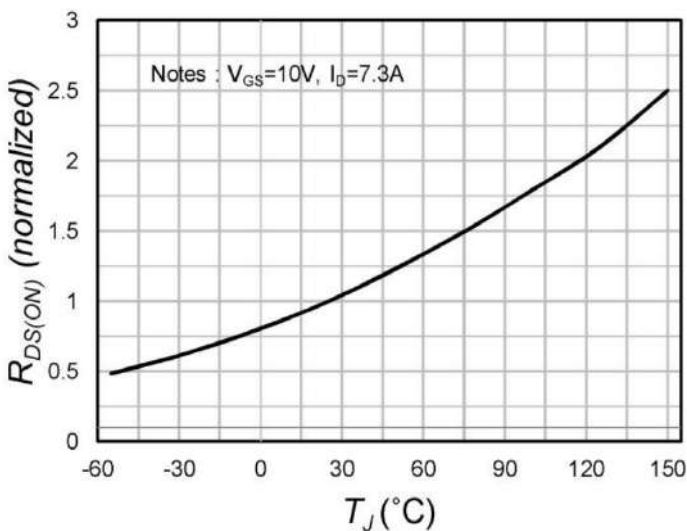


Figure 8. Breakdown Voltage vs. Junction Temperature

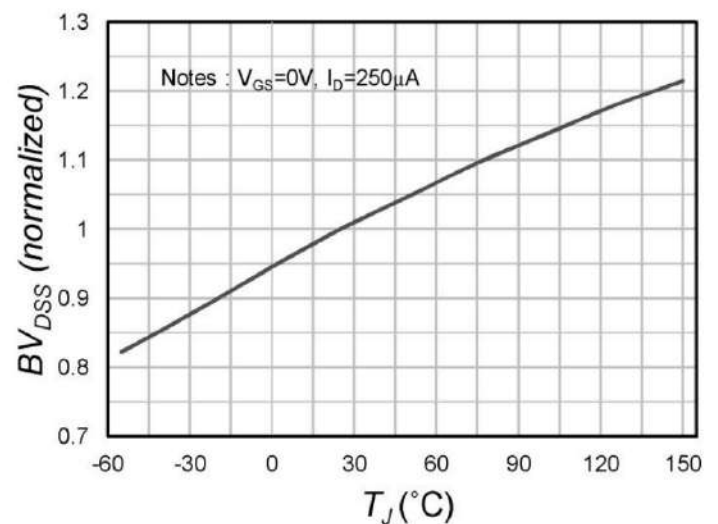


Figure 9. V_{GS} Variation vs. Junction Temperature

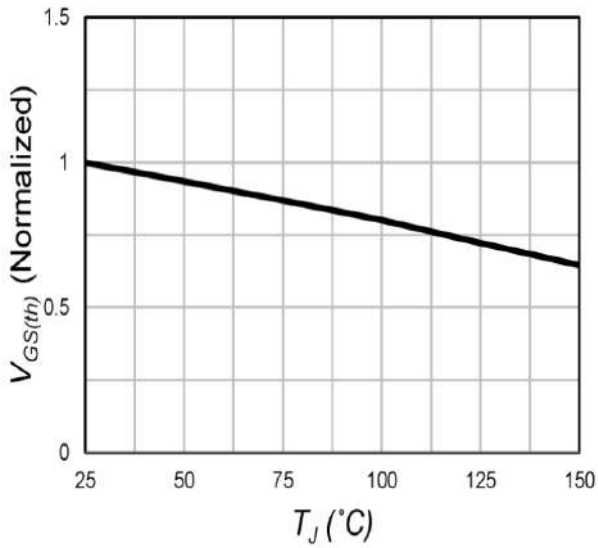


Figure 10. Transient Thermal Impedance

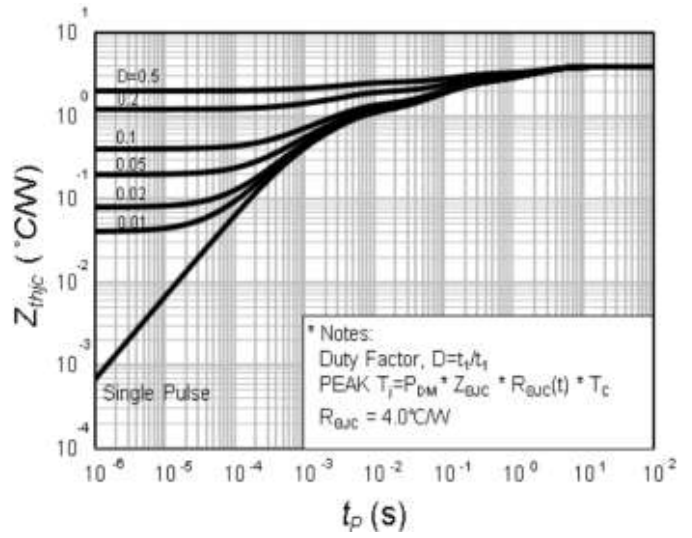
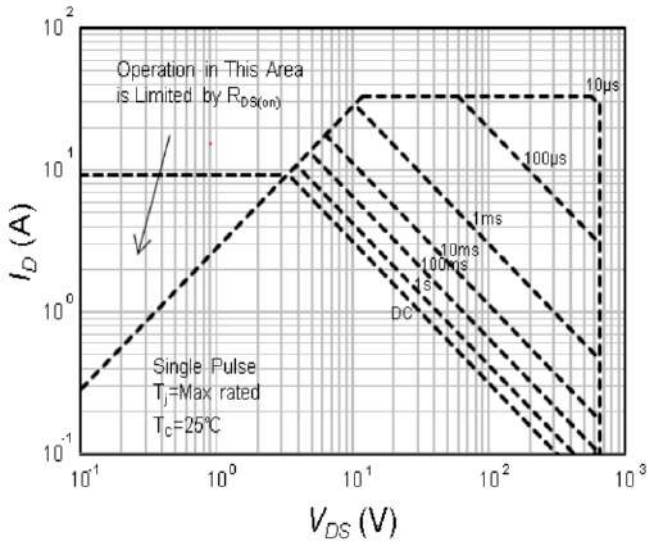


Figure 11. Safe operation area for



Test Circuits and Waveforms

Figure A: Gate Charge Test Circuit and Waveform

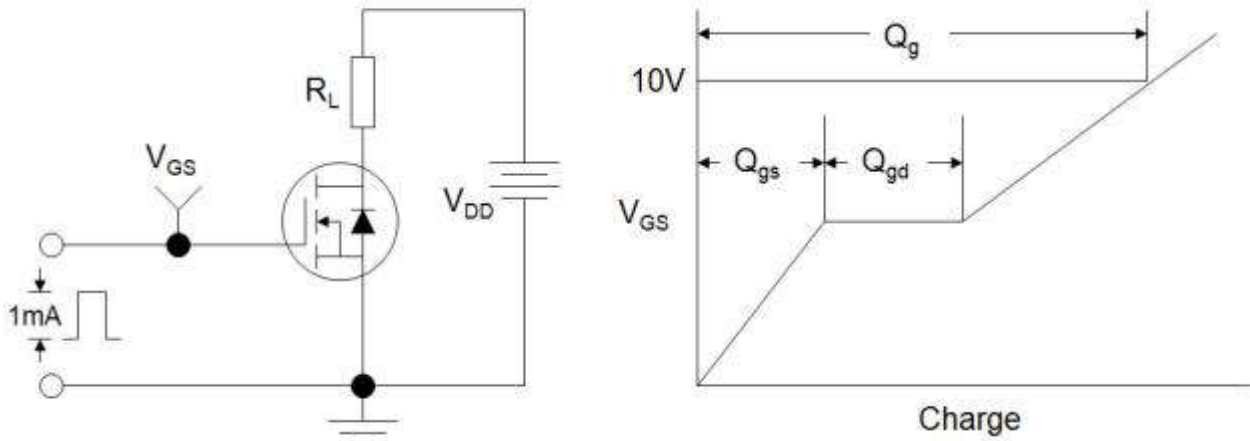


Figure B: Resistive Switching Test Circuit and Waveform

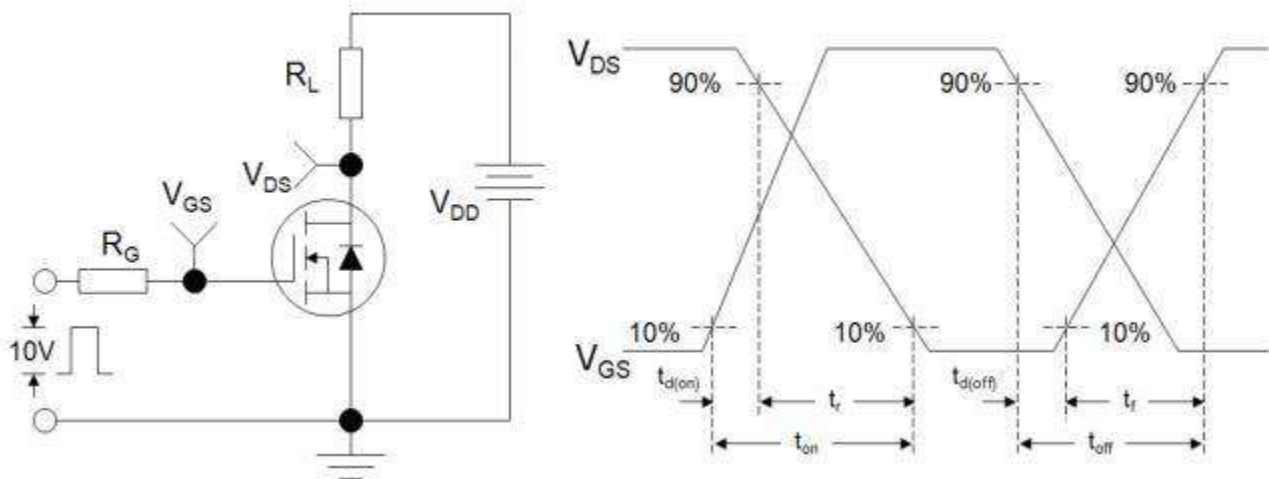
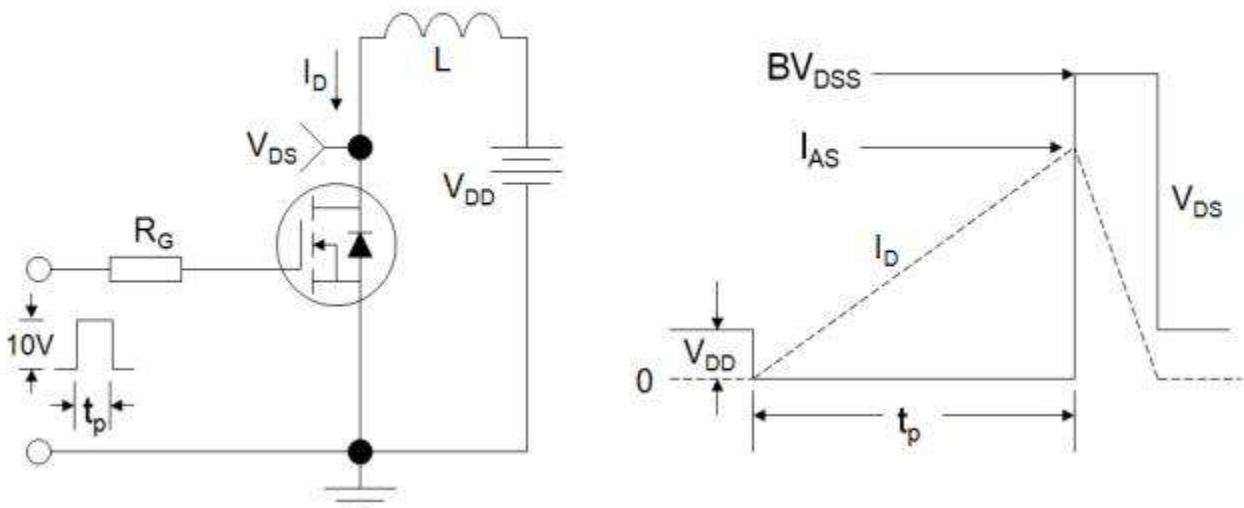
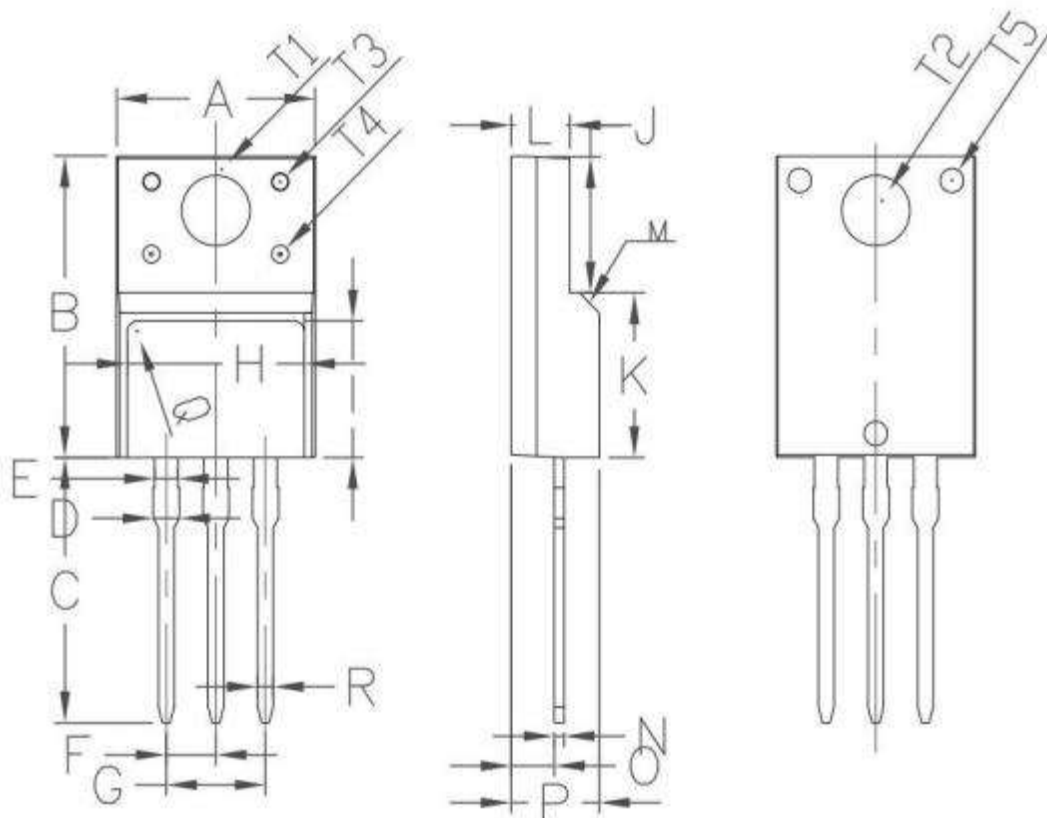


Figure C: Unclamped Inductive Switching Test Circuit and Waveform



Package outline drawing

Unit:mm



Symbol	Min	Non	Max
A	9.96	10.16	10.36
B	15.67	15.87	16.07
C	13.14	13.34	13.54
D	1.20	1.30	1.40
E		1.20	
F		2.54	
G		5.08	
H	7.60	7.80	8.00
I	7.10	7.30	7.50
J	6.48	6.68	6.88
K	8.99	9.19	9.39
L	2.34	2.54	2.74
M		45°	
N	0.49	0.50	0.52
O	2.15	2.35	2.55
P	4.50	4.70	4.90
Q		0.50	
S	4°	4.5°	5°
T1		3.45	
T2		3.18	
T3		1.50	
T4		1.20	
T5		1.50	
R	0.77	0.8	0.83

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